Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/677,335	OHISHI, SYOUJI
Examiner	**Art Unit**
Erin M. File	2611

SEARCHED			
Class	Subclass	Date	Examiner
375	326	12/7/2006	EMF

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only—see search history printout)	12/7/2006	EMF
PALM INVENTORSHIP	12/7/2006	EMF
PLUS Search	12/8/2006	EMF